

Search Notes

Application/Control No.

10/790,030

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

AOKI ET AL

Art Unit

1732

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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